

### FH5015-VB Datasheet

## N-Channel 150 V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}\left(\Omega\right)$ Max.	I <sub>D</sub> (A) <sup>g</sup>	Q <sub>g</sub> (Typ.)			
150	0.0158 at V <sub>GS</sub> = 10 V	53.7	22.8 nC			
150	0.0188 at V <sub>GS</sub> = 7.5 V	45	22.0110			

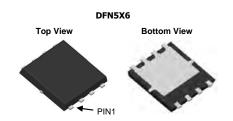
#### **FEATURES**

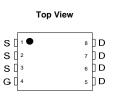
- Trench Power MOSFET
- 100 % R<sub>q</sub> and UIS Tested

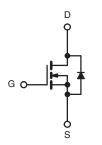


#### **APPLICATIONS**

- Fixed Telecom
- DC/DC Converter
- Primary and Secondary Side Switch







N-Channel	MOSFFT

<b>ABSOLUTE MAXIMUM RATINGS</b>	<b>S</b> (T <sub>A</sub> = 25 °C, unle	ess otherwise no	ted)	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	150	V	
Gate-Source Voltage	V <sub>GS</sub>	V <sub>GS</sub> ± 20		
	T <sub>C</sub> = 25 °C		53.7	
Continuous Drain Current (T <sub>.1</sub> = 150 °C)	T <sub>C</sub> = 70 °C		43	
Continuous Brain Guiterit (1) = 130 C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	12.8 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		10.2 <sup>b, c</sup>	A
Pulsed Drain Current (t = 300 μs)		I <sub>DM</sub> 130		
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	l <sub>a</sub>	60 <sup>a</sup>	
Continuous Source-Diam Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	5.6 <sup>b, c</sup>	
Single Pulse Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	30	
Single Pulse Avalanche Energy	L=0.11IIII	E <sub>AS</sub>	45	mJ
	T <sub>C</sub> = 25 °C		104	
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	66.6	w
Maximum Fower Dissipation	T <sub>A</sub> = 25 °C	LD.	6.25 <sup>b, c</sup>	VV
	T <sub>A</sub> = 70 °C		4 <sup>b, c</sup>	
Operating Junction and Storage Temperature Ra	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	
Soldering Recommendations (Peak Temperature		260		

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient <sup>b, f</sup>	t ≤ 10 s	$R_{thJA}$	15	20	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	0.9	1.2	J/ VV		

#### Notes:

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. The DFN5x 6 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 54 °C/W.
- g.  $T_C = 25$  °C.



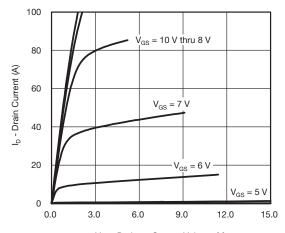
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	<u></u>				I.	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	150			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 250 μA		105		m\//0C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 9.4		mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.0		4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Oaka Walkana Busin Oamani		V <sub>DS</sub> = 150 V, V <sub>GS</sub> = 0 V			1	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 150 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 70 ^{\circ}\text{C}$			10	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	40			Α
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 20 A		0.0158		Ω
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 7.5 \text{ V}, I_D = 15 \text{ A}$		0.0188		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 20 A		30		S
Dynamic <sup>b</sup>					L	
Input Capacitance	C <sub>iss</sub>			1286		
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = 75 V, V <sub>GS</sub> = 0 V, f = 1 MHz		327		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			28		_
·		$V_{DS} = 75 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 20 \text{ A}$		31.3	47	
Total Gate Charge	$Q_g$			22.8	35	
Gate-Source Charge	harge $Q_{gs}$ $V_{DS} = 75 \text{ V}, V_{GS} = 7.5 \text{ V}, I_D = 20 \text{ A}$			8		nC
Gate-Drain Charge	Q <sub>gd</sub>			10		
Output Charge	Q <sub>oss</sub>	V <sub>DS</sub> = 75 V, V <sub>GS</sub> = 0 V		66	100	
Gate Resistance	$R_{g}$	f = 1 MHz	0.3	1	2	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			10	20	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 75 V, $R_L$ = 3.75 $\Omega$		12	24	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong$ 20 A, $V_{GEN}$ = 10 V, $R_g$ = 1 $\Omega$		15	30	
Fall Time	t <sub>f</sub>			7	14	1
Turn-On Delay Time	t <sub>d(on)</sub>			12	24	ns
Rise Time	t <sub>r</sub>	$V_{DD}$ = 75 V, $R_L$ = 3.75 $\Omega$		13	26	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong$ 20 A, $V_{GEN}$ = 7.5 V, $R_g$ = 1 $\Omega$		17	34	
Fall Time	t <sub>f</sub>			8	16	
<b>Drain-Source Body Diode Characteristic</b>	es			•	I.	
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			60	^
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				100	A
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 5 A		0.77	1.1	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			95	190	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	1 00 A dl/db 100 A/v- T 05 00		280	560	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 20 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		72		1
Reverse Recovery Rise Time	t <sub>b</sub>			23		ns

#### Notes:

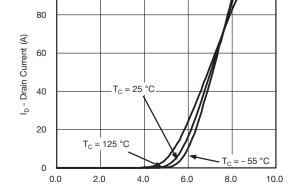
- a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





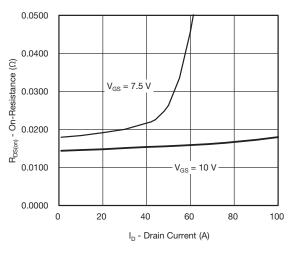
V<sub>DS</sub> - Drain-to-Source Voltage (V)



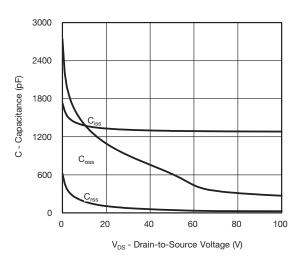
100

V<sub>GS</sub> - Gate-to-Source Voltage (V) **Transfer Characteristics** 

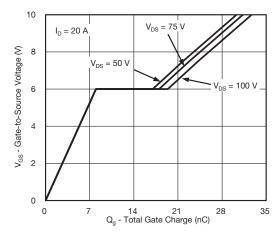
#### **Output Characteristics**



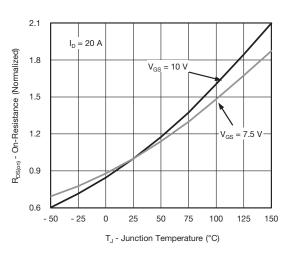
On-Resistance vs. Drain Current



Capacitance

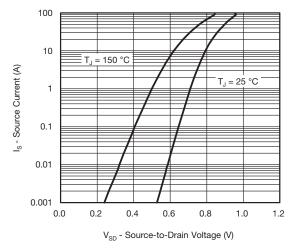


**Gate Charge** 

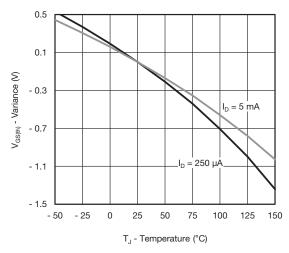


On-Resistance vs. Junction Temperature

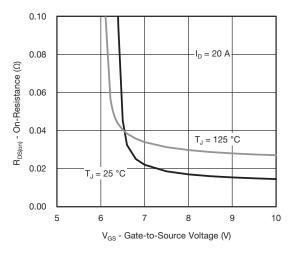




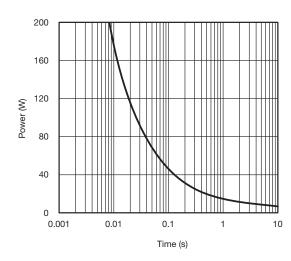
#### Source-Drain Diode Forward Voltage



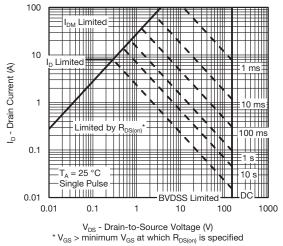
**Threshold Voltage** 



On-Resistance vs. Gate-to-Source Voltage

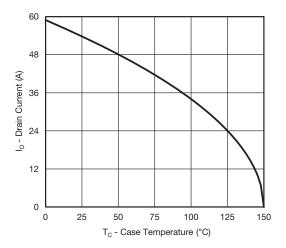


Single Pulse Power, Junction-to-Ambient

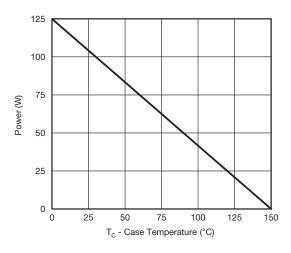


Safe Operating Area, Junction-to-Ambient

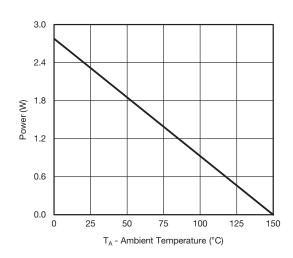




#### **Current Derating\***



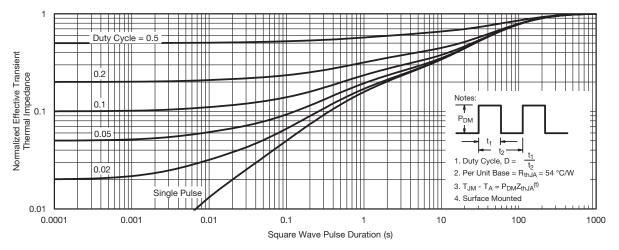




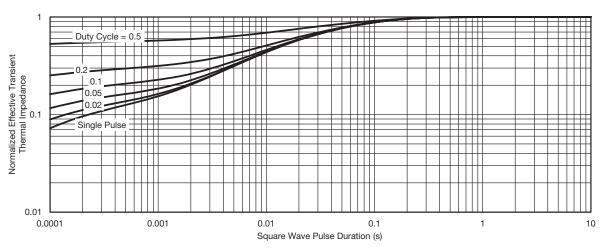
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





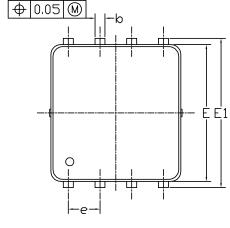
Normalized Thermal Transient Impedance, Junction-to-Ambient

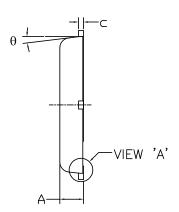


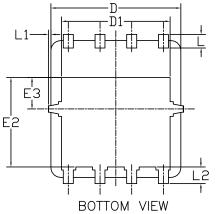
Normalized Thermal Transient Impedance, Junction-to-Case

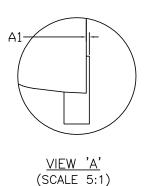


DFN5x6\_8L\_EP1\_P PACKAGE OUTLIN

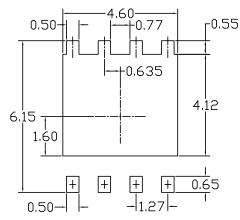








#### RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES			
SYMBOLS	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.85	0. 95	1.00	0.033	0.037	0.039	
A1	0.00		0.05	0.000		0.002	
b	0.30	0.40	0.50	0.012	0.016	0.020	
С	0.15	0. 20	0. 25	0.006	0.008	0.010	
D	5. 10	5. 20	5. 30	0. 201	0. 205	0. 209	
D1	4. 25	4. 35	4. 45	0. 167	0. 171	0. 175	
Е	5. 45	5. 55	5. 65	0. 215	0. 219	0. 222	
E1	5. 95	6.05	6. 15	0. 234	0. 238	0. 242	
E2	3. 525	3. 625	3. 725	0. 139	0. 143	0. 147	
E3	1. 175	1. 275	1. 375	0.046	0.050	0.054	
e	1. 27 BSC			0. 050 BSC			
L	0.45	0. 55	0.65	0.018	0.022	0.026	
L1	0		0. 15	0		0.006	
L2	0.68 REF			0.027 REF			
θ	0°		10°	0°		10°	

#### NOTE

- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
- 2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

UNIT: mm



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